



IMPACT advanced characterization chambers details

■ XPS (Thermo Fisher)

- ✓ **pAR-XPS** (parallel angle resolved XPS)
- ✓ Angles from **20° to 80° without sample tilt**
- ✓ Spot size 20 to 400µm
- ✓ Ion beam Ar etching for abrasion

■ Ellipsometry (Horiba Jobin Yvon)

- ✓ **IR to V-UV : 12 µm (0,1 eV) to 145 nm (8,55 eV)**
- ✓ Azimutal rotation
- ✓ **Sample heating (up to 450°C)**

■ Photolum / Raman (Horiba Jobin Yvon)

- ✓ Based on Labram HR (best in class Raman system)
- ✓ **IR to UV (3 lasers : 355nm / 532nm / 1064 nm)**
- ✓ Confocal measurements (depth resolution)
- ✓ Spatial resolution < 3µm

■ Cleavage

- ✓ **Glove box with vacuum capability or controlled atmosphere**
- ✓ Manual Cleaving under controlled atmosphere
- ✓ Possibility of sample's transfer to PFNC instruments by vacuum carrier



Small samples to 300 mm loading capability

